

Search Notes

Application/Control No.

10/651,821

Examiner

Rick K. Chang

Applicant(s)/Patent under
Reexamination

MATHIEU ET AL.

Art Unit

3729

SEARCHED

Class	Subclass	Date	Examiner
search	updated	12/12/2005	RC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR